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United States Patent [19]

Okada et al.

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[54] **PROBE FOR A SCANNING TUNNELING MICROSCOPE**

[75] Inventors: **Takao Okada; Tsugiko Takase; Shuzo Mishima,** all of Hachioji; **Hisanari Shimazu,** Akishima; **Akira Yagi,** Sagamihara; **Hiroko Ota,** Hachioji; **Hirofumi Miyamoto,** Hachioji; **Takaaki Takenobu,** Hachioji, all of Japan

[73] Assignee: **Olympus Optical Co., Ltd.,** Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **621,550**

[22] Filed: **Dec. 3, 1990**

[52] **U.S. Cl.** **D16/136**

[58] **Field of Search** D16/136, 134; 250/309, 250/310, 311; 359/385, 390

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Primary Examiner—A. Hugo Word
Assistant Examiner—Paula A. Mortimer
Attorney, Agent, or Firm—Frishauf, Holtz, Goodman & Woodward

[57] **CLAIM**

The ornamental design for a probe for a scanning tunneling microscope, as shown and described.

DESCRIPTION

FIG. **1** is a top, front and side perspective view of a probe for a scanning tunneling microscope showing our new design;

FIG. **2** is a front elevational view thereof, a rear elevational view, a right side elevational view and a left side elevational view being identical to the front;

FIG. **3** is a top plan view thereof;

FIG. **4** is a bottom plan view thereof;

FIG. **5** is a cross-sectional view thereof taken on line **5—5** in FIG. **2**; and,

FIG. **6** is a cross-sectional view thereof taken on line **6—6** in FIG. **2.**

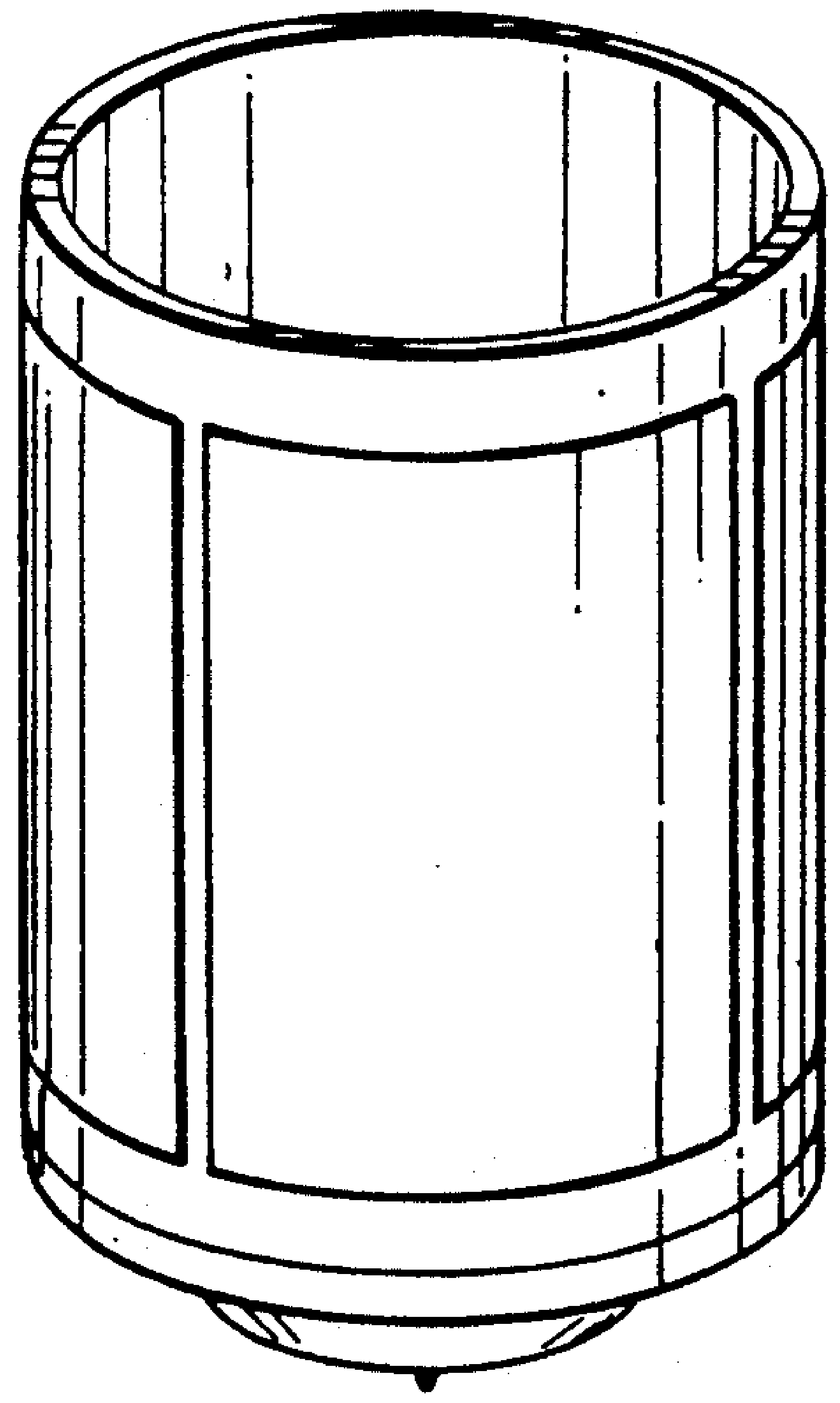

FIG. 1

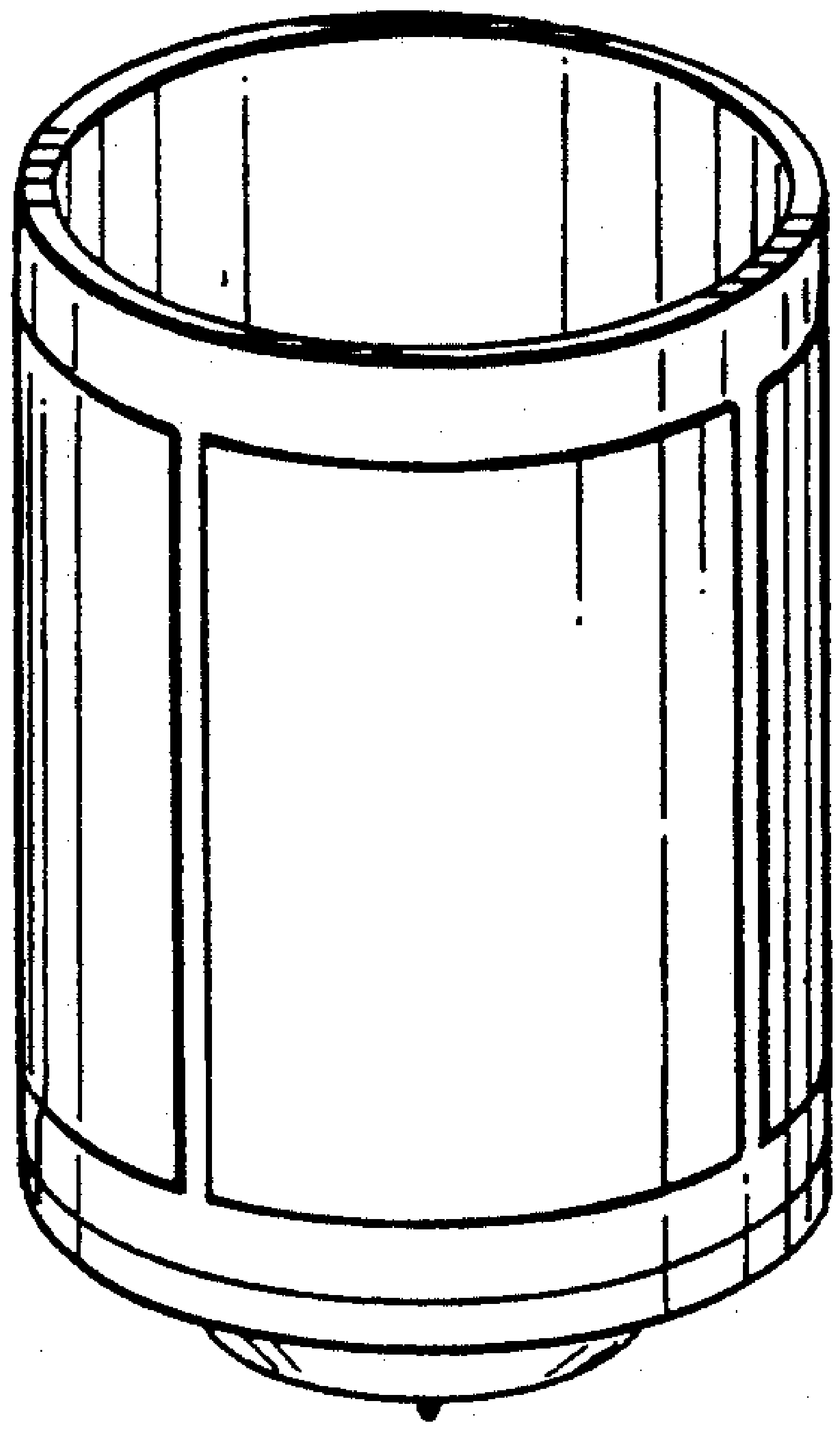

FIG. 2

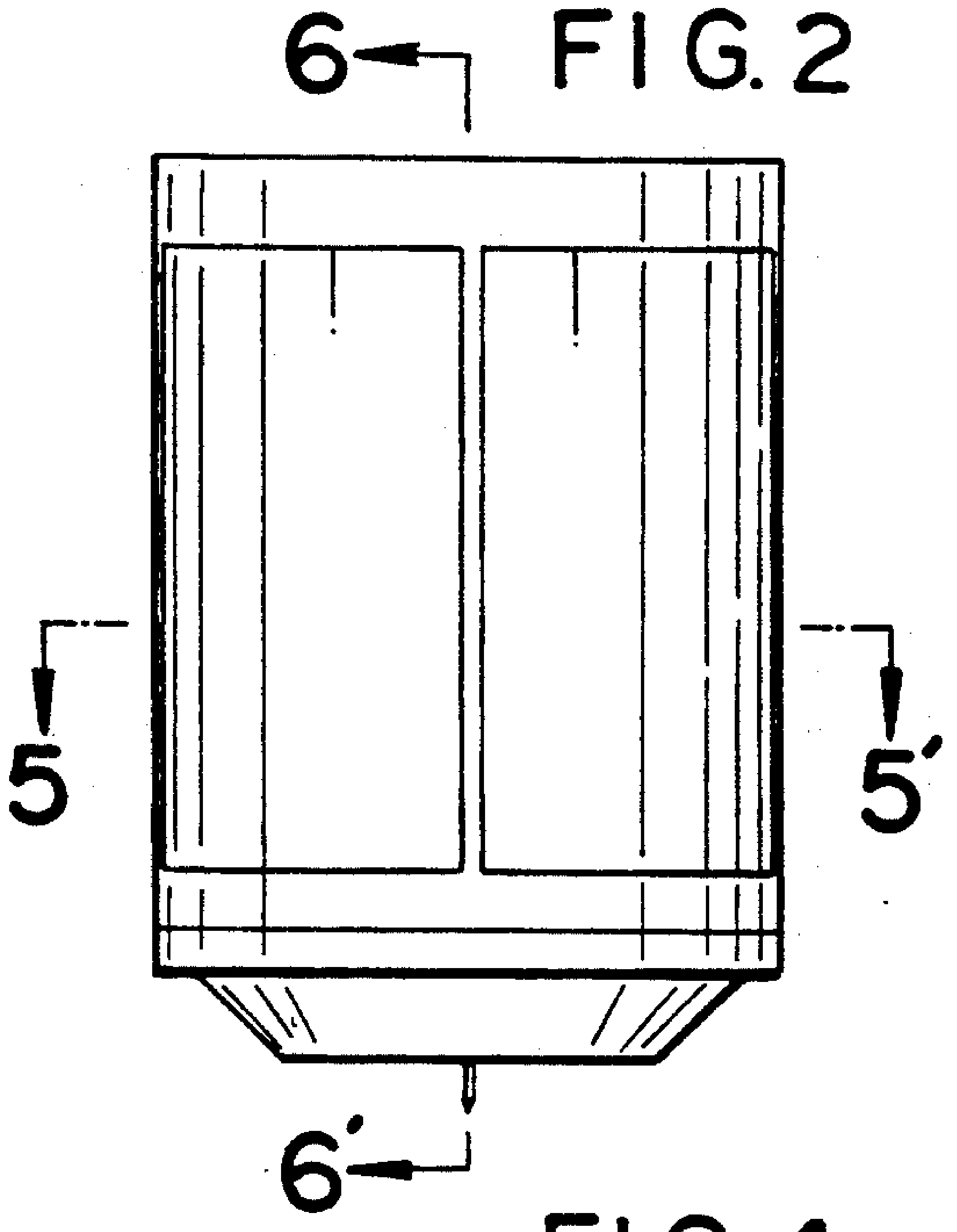

FIG. 3

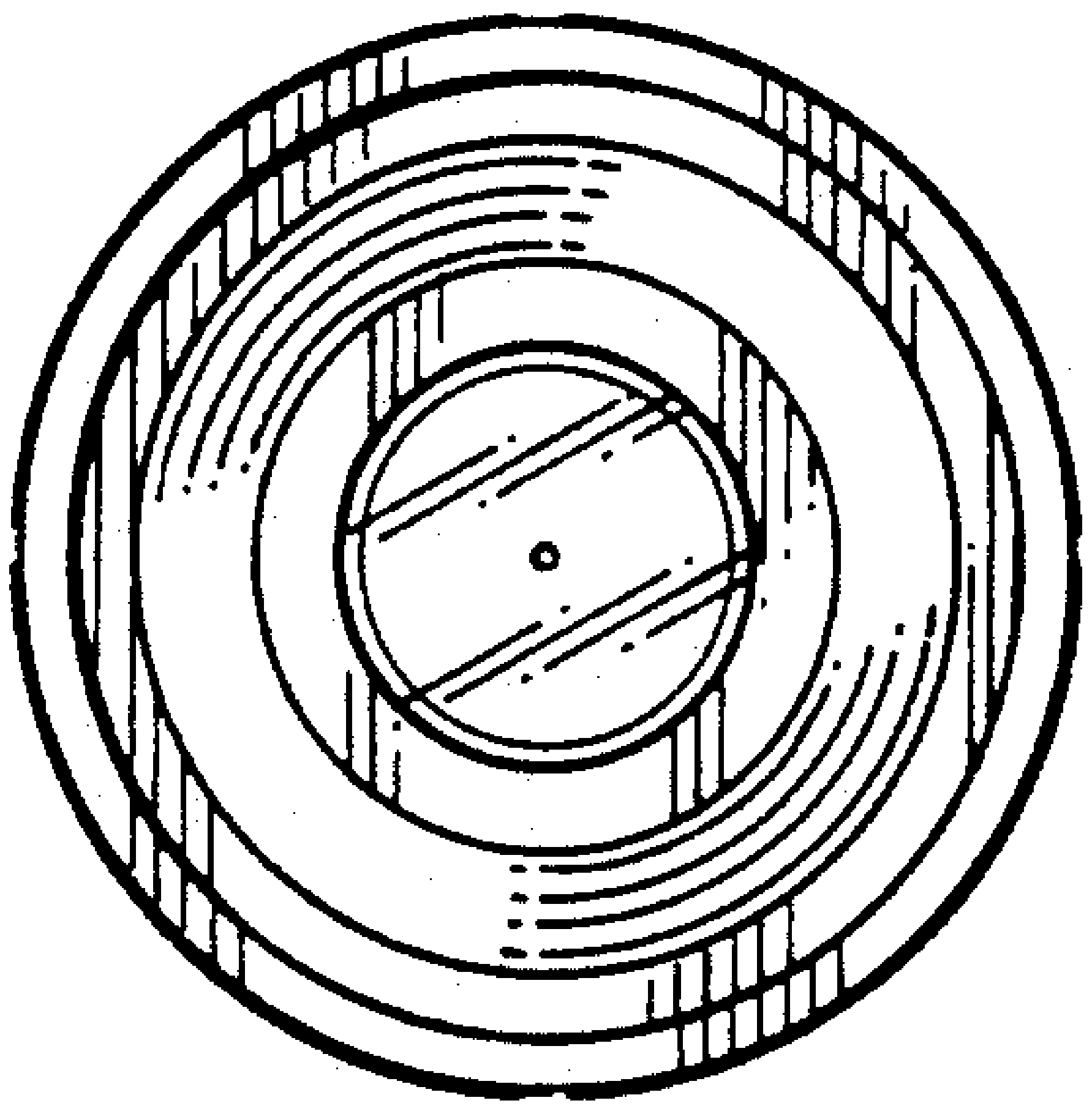

FIG. 4

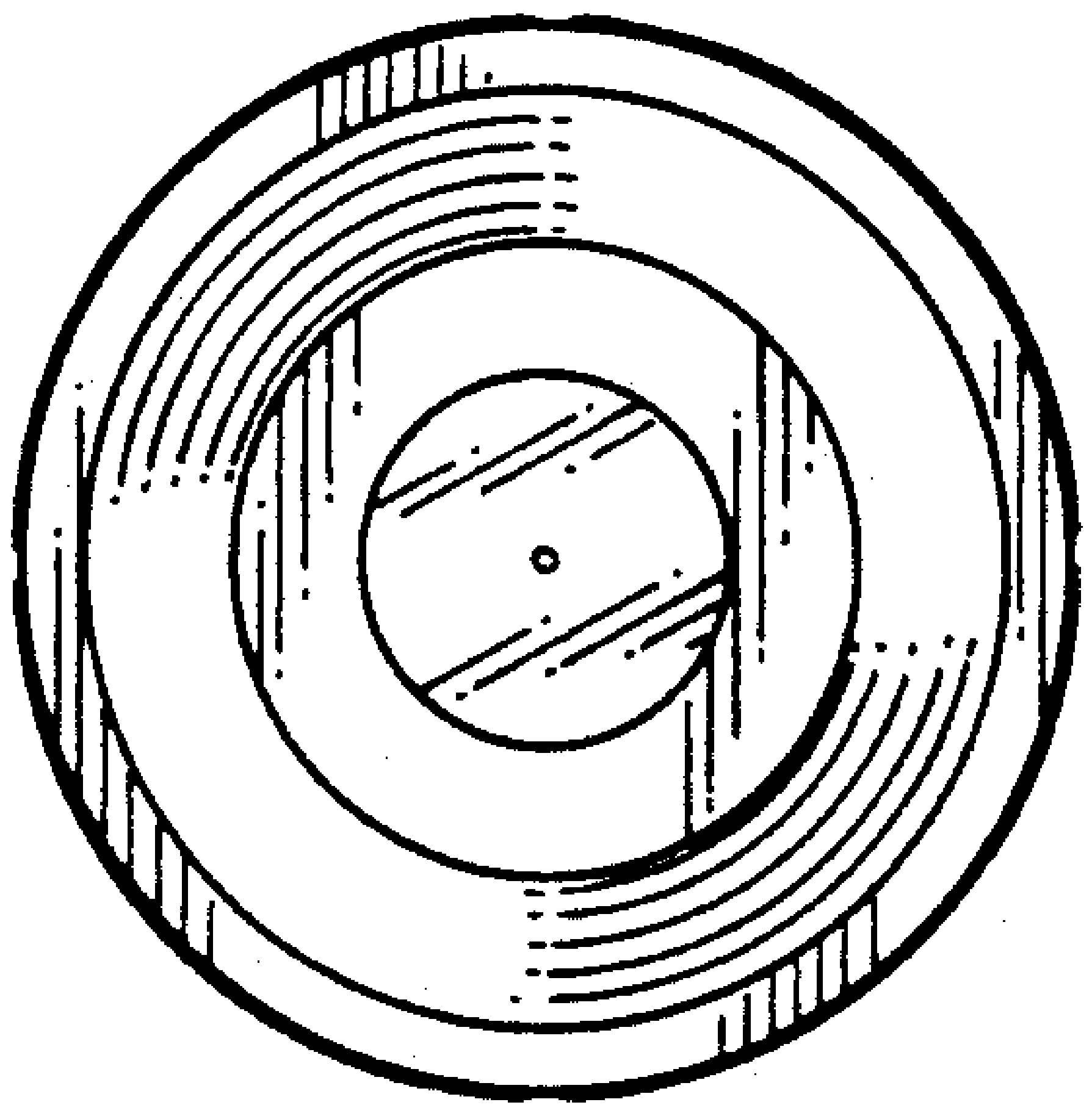

FIG. 5

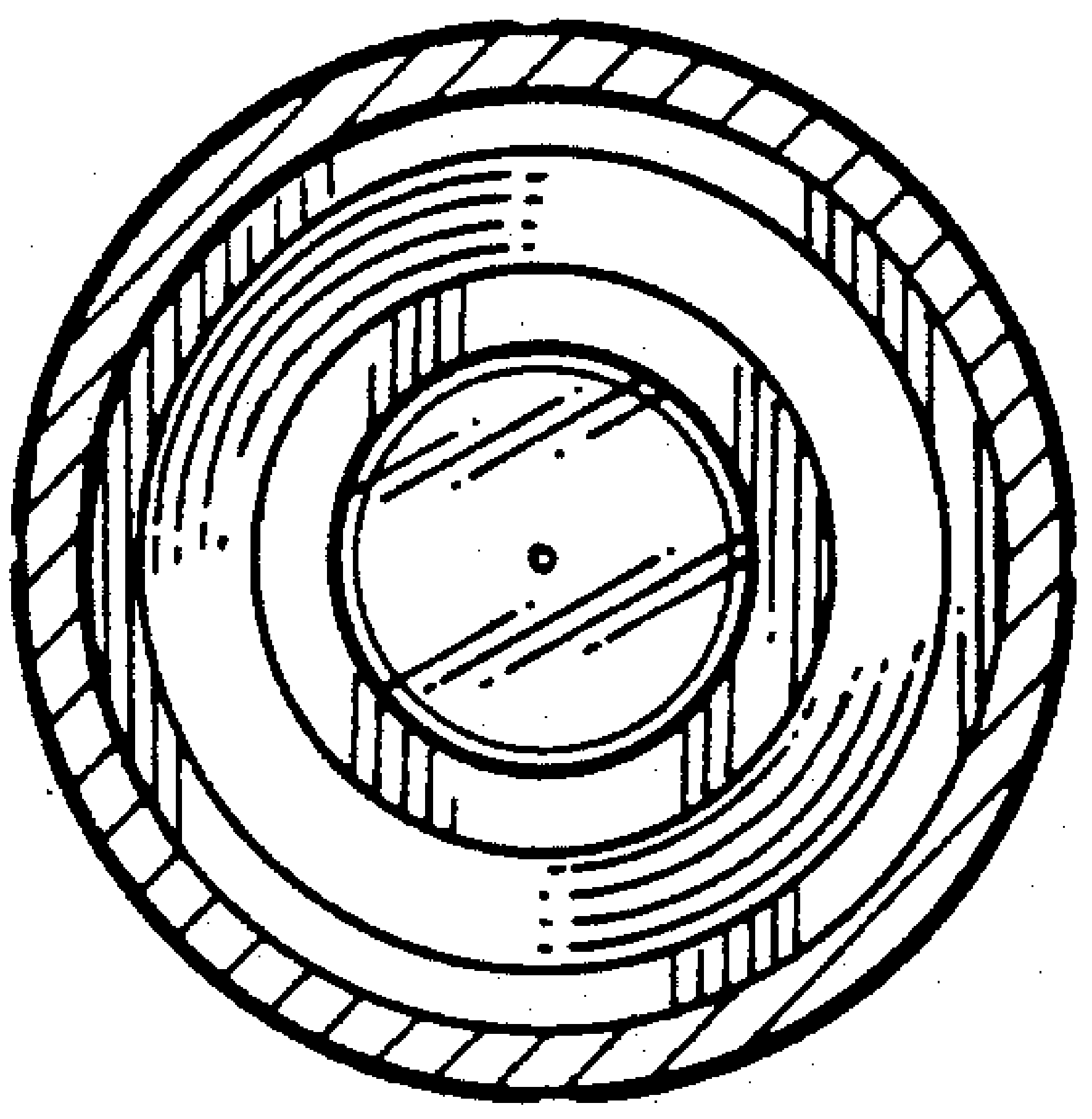

FIG. 6